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## INFORMATION DISCLOSURE CITATION

Atty Docket  
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Applicant

FINE, et al.

Filing Date  
Nov. 6, 2003

Group Art Unit  
Not yet assigned

## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Issue Date	Name	Class	Sub-Class	Filing Date
<i>mk</i>	AD	5,348,002	Sep. 20, 1994	Caro		Apr. 23, 1992
<i>mk</i>	AB	5,792,668	Aug. 11, 1998	Fuller et al.		Apr. 15, 1996
<i>mk</i>	AC	5,941,821	Aug. 24, 1999	Chou		Nov. 25, 1997
<i>mk</i>	AD	6,049,728	Apr. 11, 2000	Chou		Nov. 12, 1998
<i>mk</i>	AE	6,400,972	June 4, 2002	Fine		Dec. 21, 1999
<i>mk</i>	AF	6,466,806	Oct. 15, 2002	Geva et al.		May 17, 2000
<i>mk</i>	AG	2002/0155615	Oct. 24, 2002	Novikov et al.		Feb. 5, 2002

## FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Sub-Class	Translation
<i>mk</i> AH	WO 01/96872	Dec. 20, 2001	WIPO		N/A
<i>mk</i> AI	WO 01/45553	June 28, 2001	WIPO		N/A
<i>mk</i> AJ	WO 02/069791	Sep. 12, 2002	WIPO		N/A
<i>mk</i> AK	0 282 234	Sep. 14, 1988	EP		N/A
<i>mk</i> AL	WO 00/43759	July 27, 2000	WIPO		N/A

## OTHER (Including Author, Title, Date, Pertinent Pages, etc.)

AM	Feldman, Yuri, et al., "Time domain dielectric spectroscopy: An advanced measuring system". Rev. Sci. Instrum., vol. 67, no. 9, pp. 3208-3216, September 1996.
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Examiner

*Matthew Kerner*

Date Considered

*4/13/2005*

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP § 609.  
Draw line through citation if not in conformance and not considered.  
Include copy of this form with next communication to Applicant.